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## Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

## Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

### Details

Product Status	Obsolete
Number of LABs/CLBs	5000
Number of Logic Elements/Cells	40000
Total RAM Bits	906240
Number of I/O	540
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	672-BBGA
Supplier Device Package	672-FPBGA (27x27)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/lattice-semiconductor/lfxp2-40e-5f672i">https://www.e-xfl.com/product-detail/lattice-semiconductor/lfxp2-40e-5f672i</a>

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## Routing

There are many resources provided in the LatticeXP2 devices to route signals individually or as busses with related control signals. The routing resources consist of switching circuitry, buffers and metal interconnect (routing) segments.

The inter-PFU connections are made with x1 (spans two PFU), x2 (spans three PFU) or x6 (spans seven PFU) connections. The x1 and x2 connections provide fast and efficient connections in horizontal and vertical directions. The x2 and x6 resources are buffered to allow both short and long connections routing between PFUs.

The LatticeXP2 family has an enhanced routing architecture to produce a compact design. The Diamond design tool takes the output of the synthesis tool and places and routes the design. Generally, the place and route tool is completely automatic, although an interactive routing editor is available to optimize the design.

## sysCLOCK Phase Locked Loops (PLL)

The sysCLOCK PLLs provide the ability to synthesize clock frequencies. The LatticeXP2 family supports between two and four full featured General Purpose PLLs (GPLL). The architecture of the GPLL is shown in Figure 2-4.

CLKI, the PLL reference frequency, is provided either from the pin or from routing; it feeds into the Input Clock Divider block. CLKFB, the feedback signal, is generated from CLKOP (the primary clock output) or from a user clock pin/logic. CLKFB feeds into the Feedback Divider and is used to multiply the reference frequency.

Both the input path and feedback signals enter the Voltage Controlled Oscillator (VCO) block. The phase and frequency of the VCO are determined from the input path and feedback signals. A LOCK signal is generated by the VCO to indicate that the VCO is locked with the input clock signal.

The output of the VCO feeds into the CLKOP Divider, a post-scalar divider. The duty cycle of the CLKOP Divider output can be fine tuned using the Duty Trim block, which creates the CLKOP signal. By allowing the VCO to operate at higher frequencies than CLKOP, the frequency range of the GPLL is expanded. The output of the CLKOP Divider is passed through the CLKOK Divider, a secondary clock divider, to generate lower frequencies for the CLKOK output. For applications that require even lower frequencies, the CLKOP signal is passed through a divide-by-three divider to produce the CLKOK2 output. The CLKOK2 output is provided for applications that use source synchronous logic. The Phase/Duty Cycle/Duty Trim block is used to adjust the phase and duty cycle of the CLKOP Divider output to generate the CLKOS signal. The phase/duty cycle setting can be pre-programmed or dynamically adjusted.

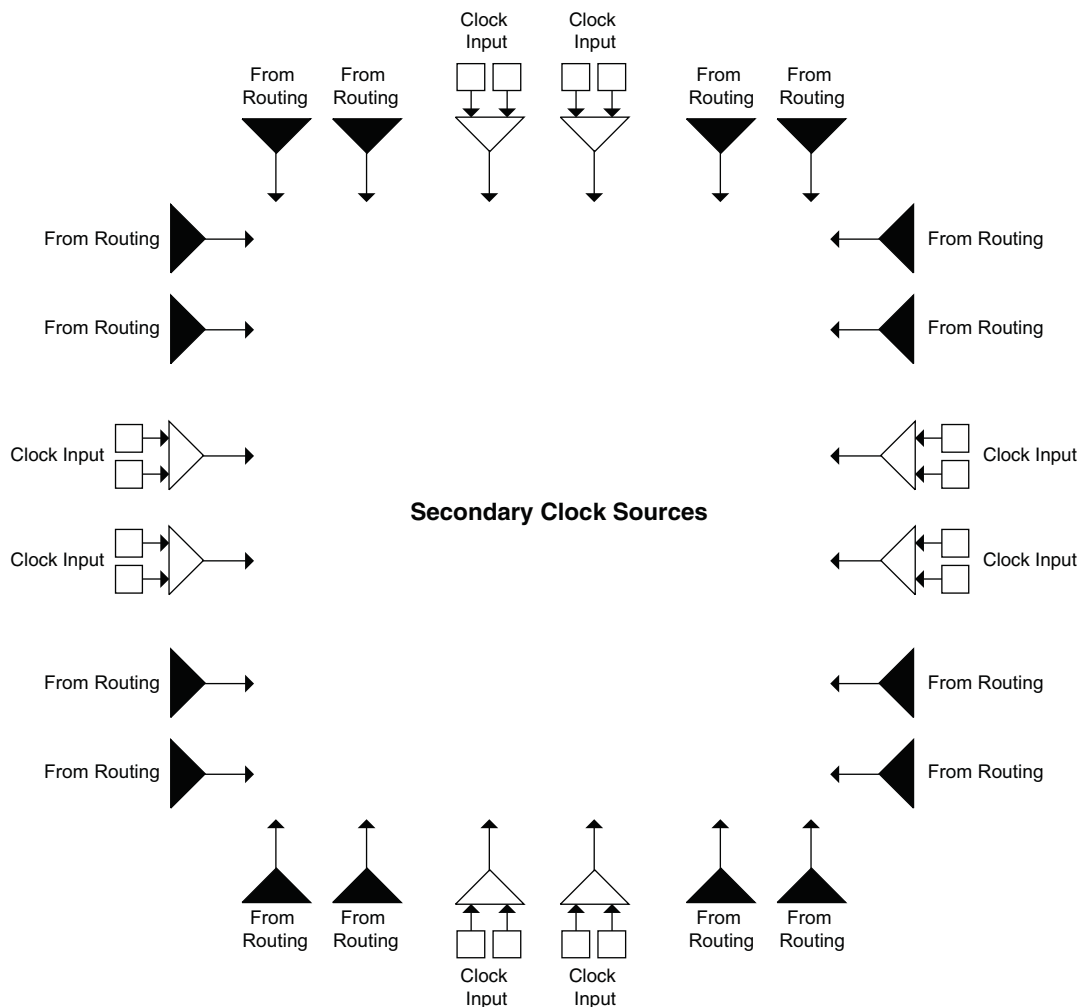
The clock outputs from the GPLL; CLKOP, CLKOK, CLKOK2 and CLKOS, are fed to the clock distribution network.

For further information on the GPLL please see TN1126, [LatticeXP2 sysCLOCK PLL Design and Usage Guide](#).

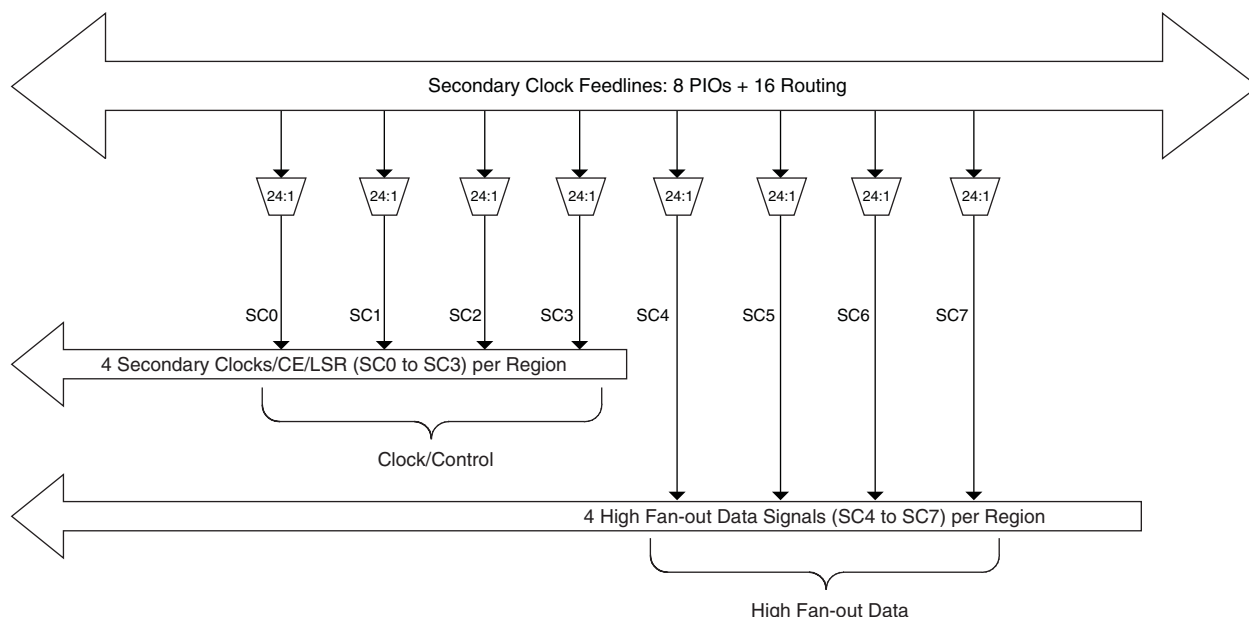
## Secondary Clock/Control Sources

LatticeXP2 devices derive secondary clocks (SC0 through SC7) from eight dedicated clock input pads and the rest from routing. Figure 2-7 shows the secondary clock sources.

**Figure 2-7. Secondary Clock Sources**



**Figure 2-12. Secondary Clock Selection**

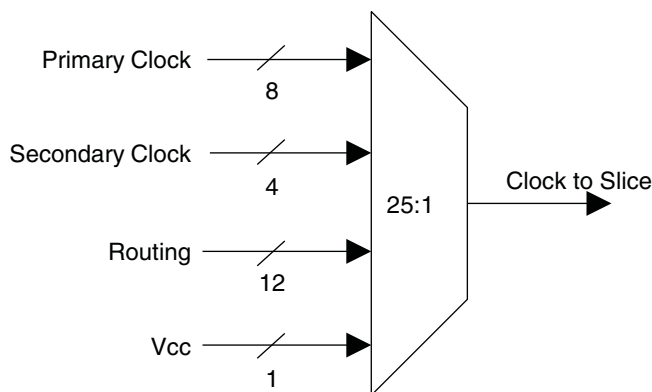


## Slice Clock Selection

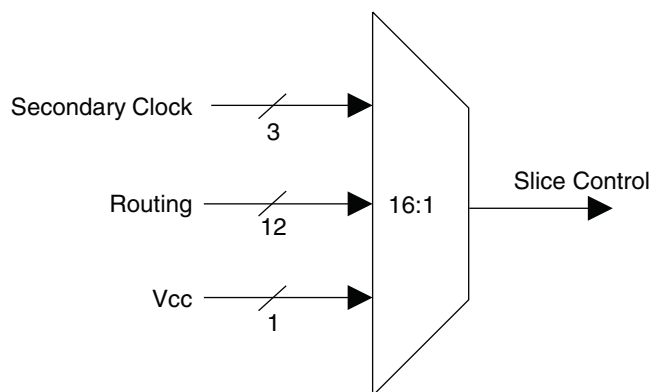
Figure 2-13 shows the clock selections and Figure 2-14 shows the control selections for Slice0 through Slice2. All the primary clocks and the four secondary clocks are routed to this clock selection mux. Other signals, via routing, can be used as clock inputs to the slices. Slice controls are generated from the secondary clocks or other signals connected via routing.

If none of the signals are selected for both clock and control, then the default value of the mux output is 1. Slice 3 does not have any registers; therefore it does not have the clock or control muxes.

**Figure 2-13. Slice0 through Slice2 Clock Selection**



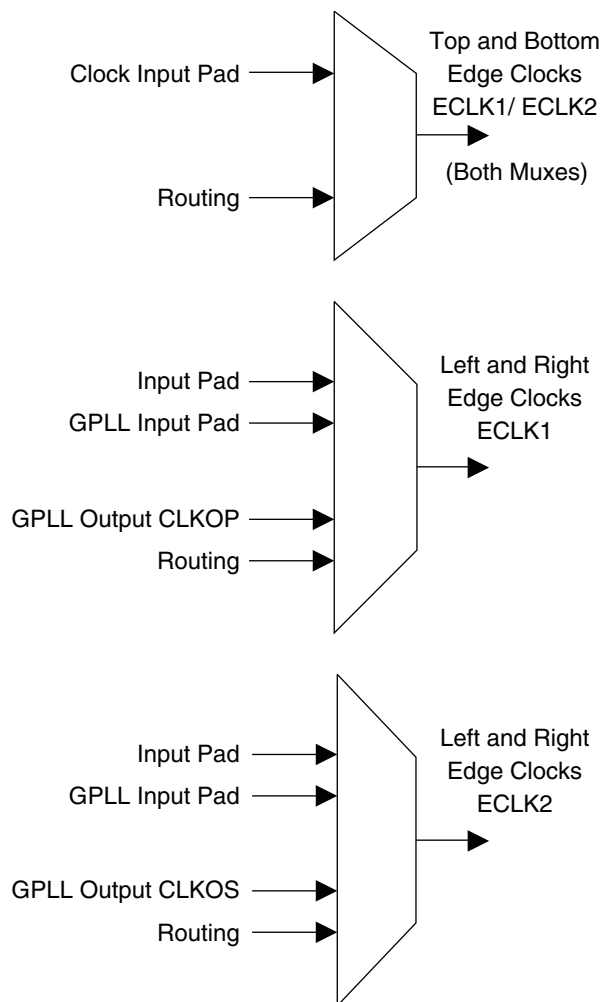
**Figure 2-14. Slice0 through Slice2 Control Selection**



## Edge Clock Routing

LatticeXP2 devices have eight high-speed edge clocks that are intended for use with the PIOs in the implementation of high-speed interfaces. Each device has two edge clocks per edge. Figure 2-15 shows the selection muxes for these clocks.

**Figure 2-15. Edge Clock Mux Connections**



## sysMEM Memory

LatticeXP2 devices contains a number of sysMEM Embedded Block RAM (EBR). The EBR consists of 18 Kbit RAM with dedicated input and output registers.

### sysMEM Memory Block

The sysMEM block can implement single port, dual port or pseudo dual port memories. Each block can be used in a variety of depths and widths as shown in Table 2-5. FIFOs can be implemented in sysMEM EBR blocks by using support logic with PFUs. The EBR block supports an optional parity bit for each data byte to facilitate parity checking. EBR blocks provide byte-enable support for configurations with 18-bit and 36-bit data widths.

**Table 2-5. sysMEM Block Configurations**

Memory Mode	Configurations
Single Port	16,384 x 1 8,192 x 2 4,096 x 4 2,048 x 9 1,024 x 18 512 x 36
True Dual Port	16,384 x 1 8,192 x 2 4,096 x 4 2,048 x 9 1,024 x 18
Pseudo Dual Port	16,384 x 1 8,192 x 2 4,096 x 4 2,048 x 9 1,024 x 18 512 x 36

### Bus Size Matching

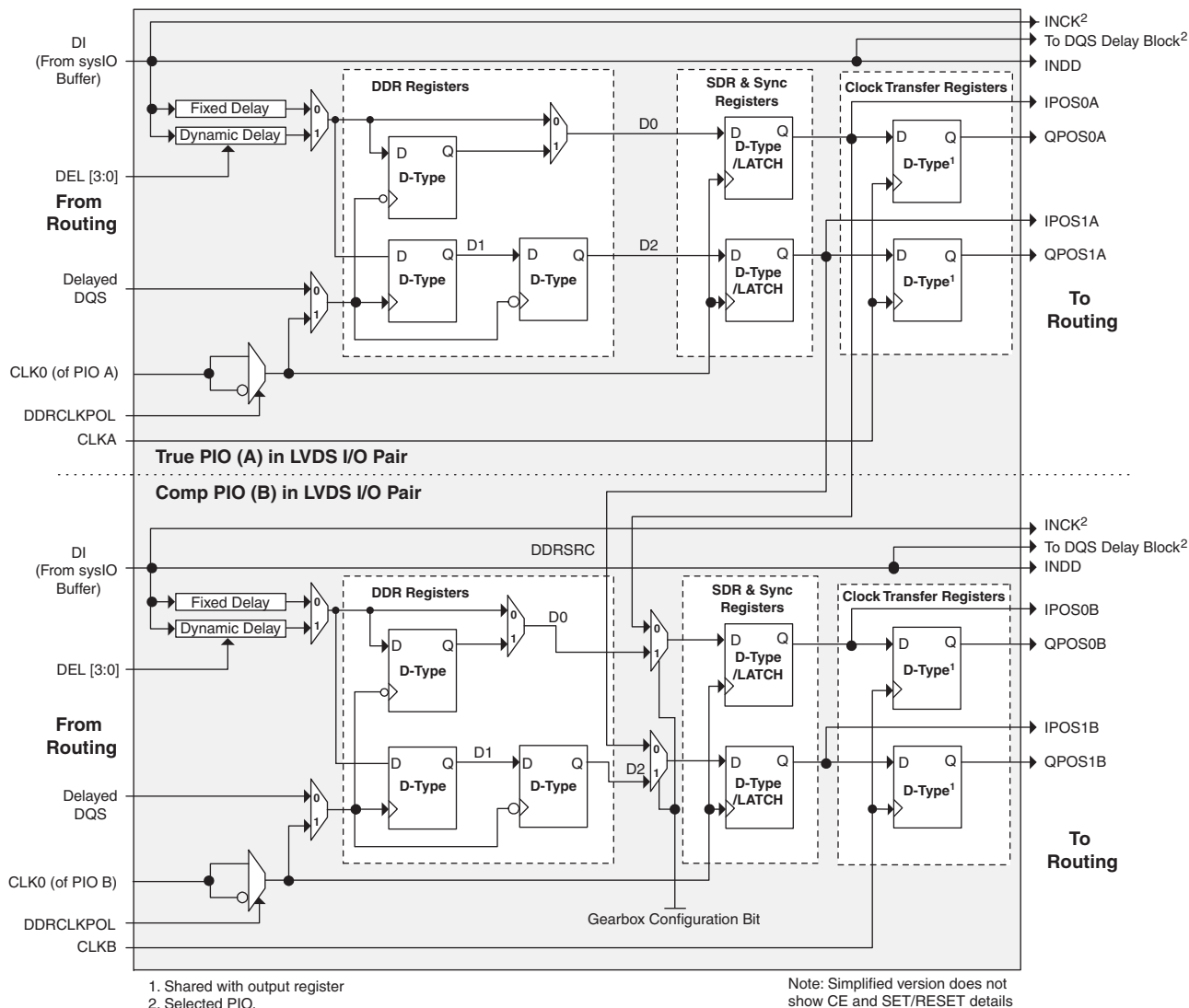
All of the multi-port memory modes support different widths on each of the ports. The RAM bits are mapped LSB word 0 to MSB word 0, LSB word 1 to MSB word 1, and so on. Although the word size and number of words for each port varies, this mapping scheme applies to each port.

### FlashBAK EBR Content Storage

All the EBR memory in the LatticeXP2 is shadowed by Flash memory. Optionally, initialization values for the memory blocks can be defined using the Lattice Diamond design tools. The initialization values are loaded into the Flash memory during device programming and into the SRAM at power up or whenever the device is reconfigured. This feature is ideal for the storage of a variety of information such as look-up tables and microprocessor code. It is also possible to write the current contents of the EBR memory back to Flash memory. This capability is useful for the storage of data such as error codes and calibration information. For additional information on the FlashBAK capability see TN1137, [LatticeXP2 Memory Usage Guide](#).

The signal DDRCLKPOL controls the polarity of the clock used in the synchronization registers. It ensures adequate timing when data is transferred from the DQS to system clock domain. For further discussion on this topic, see the DDR Memory section of this data sheet.

**Figure 2-26. Input Register Block**



## Output Register Block

The output register block provides the ability to register signals from the core of the device before they are passed to the sysIO buffers. The blocks on the PIOs on the left, right and bottom contain registers for SDR operation that are combined with an additional latch for DDR operation. Figure 2-27 shows the diagram of the Output Register Block for PIOs.

In SDR mode, ONEG0 feeds one of the flip-flops that then feeds the output. The flip-flop can be configured as a D-type or latch. In DDR mode, ONEG0 and OPOS0 are fed into registers on the positive edge of the clock. At the next clock cycle the registered OPOS0 is latched. A multiplexer running off the same clock cycle selects the correct register to feed the output (D0).

By combining output blocks of the complementary PIOs and sharing some registers from input blocks, a gearbox function can be implemented, to take four data streams ONEG0A, ONEG1A, ONEG1B and ONEG1B. Figure 2-27

## Tristate Register Block

The tristate register block provides the ability to register tri-state control signals from the core of the device before they are passed to the sysIO buffers. The block contains a register for SDR operation and an additional latch for DDR operation. Figure 2-27 shows the Tristate Register Block with the Output Block

In SDR mode, ONEG1 feeds one of the flip-flops that then feeds the output. The flip-flop can be configured as D-type or latch. In DDR mode, ONEG1 and OPOS1 are fed into registers on the positive edge of the clock. Then in the next clock the registered OPOS1 is latched. A multiplexer running off the same clock cycle selects the correct register for feeding to the output (D0).

## Control Logic Block

The control logic block allows the selection and modification of control signals for use in the PIO block. A clock signal is selected from general purpose routing, ECLK1, ECLK2 or a DQS signal (from the programmable DQS pin) and is provided to the input register block. The clock can optionally be inverted.

## DDR Memory Support

PICs have additional circuitry to allow implementation of high speed source synchronous and DDR memory interfaces.

PICs have registered elements that support DDR memory interfaces. Interfaces on the left and right edges are designed for DDR memories that support 16 bits of data, whereas interfaces on the top and bottom are designed for memories that support 18 bits of data. One of every 16 PIOs on the left and right and one of every 18 PIOs on the top and bottom contain delay elements to facilitate the generation of DQS signals. The DQS signals feed the DQS buses which span the set of 16 or 18 PIOs. Figure 2-28 and Figure 2-29 show the DQS pin assignments in each set of PIOs.

The exact DQS pins are shown in a dual function in the Logic Signal Connections table in this data sheet. Additional detail is provided in the Signal Descriptions table. The DQS signal from the bus is used to strobe the DDR data from the memory into input register blocks. For additional information on using DDR memory support please see TN1138, [LatticeXP2 High Speed I/O Interface](#).



LatticeXP2 devices contain two types of sysIO buffer pairs.

**1. Top and Bottom (Banks 0, 1, 4 and 5) sysIO Buffer Pairs (Single-Ended Outputs Only)**

The sysIO buffer pairs in the top banks of the device consist of two single-ended output drivers and two sets of single-ended input buffers (both ratioed and referenced). One of the referenced input buffers can also be configured as a differential input.

The two pads in the pair are described as “true” and “comp”, where the true pad is associated with the positive side of the differential input buffer and the comp (complementary) pad is associated with the negative side of the differential input buffer.

Only the I/Os on the top and bottom banks have programmable PCI clamps.

**2. Left and Right (Banks 2, 3, 6 and 7) sysIO Buffer Pairs (50% Differential and 100% Single-Ended Outputs)**

The sysIO buffer pairs in the left and right banks of the device consist of two single-ended output drivers, two sets of single-ended input buffers (both ratioed and referenced) and one differential output driver. One of the referenced input buffers can also be configured as a differential input.

The two pads in the pair are described as “true” and “comp”, where the true pad is associated with the positive side of the differential I/O, and the comp pad is associated with the negative side of the differential I/O.

LVDS differential output drivers are available on 50% of the buffer pairs on the left and right banks.

### **Typical sysIO I/O Behavior During Power-up**

The internal power-on-reset (POR) signal is deactivated when  $V_{CC}$ ,  $V_{CCCONFIG}$  ( $V_{CCIO7}$ ) and  $V_{CCAUX}$  have reached satisfactory levels. After the POR signal is deactivated, the FPGA core logic becomes active. It is the user's responsibility to ensure that all other  $V_{CCIO}$  banks are active with valid input logic levels to properly control the output logic states of all the I/O banks that are critical to the application. During power up and before the FPGA core logic becomes active, all user I/Os will be high-impedance with weak pull-up. Please refer to TN1136, [LatticeXP2 sysIO Usage Guide](#) for additional information.

The  $V_{CC}$  and  $V_{CCAUX}$  supply the power to the FPGA core fabric, whereas the  $V_{CCIO}$  supplies power to the I/O buffers. In order to simplify system design while providing consistent and predictable I/O behavior, it is recommended that the I/O buffers be powered-up prior to the FPGA core fabric.  $V_{CCIO}$  supplies should be powered-up before or together with the  $V_{CC}$  and  $V_{CCAUX}$  supplies.

### **Supported sysIO Standards**

The LatticeXP2 sysIO buffer supports both single-ended and differential standards. Single-ended standards can be further subdivided into LVCMOS, LVTTL and other standards. The buffers support the LVTTL, LVCMOS 1.2V, 1.5V, 1.8V, 2.5V and 3.3V standards. In the LVCMOS and LVTTL modes, the buffer has individual configuration options for drive strength, bus maintenance (weak pull-up, weak pull-down, or a bus-keeper latch) and open drain. Other single-ended standards supported include SSTL and HSTL. Differential standards supported include LVDS, MLVDS, BLVDS, LVPECL, RSDS, differential SSTL and differential HSTL. Tables 2-12 and 2-13 show the I/O standards (together with their supply and reference voltages) supported by LatticeXP2 devices. For further information on utilizing the sysIO buffer to support a variety of standards please see TN1136, [LatticeXP2 sysIO Usage Guide](#).

original backup configuration and try again. This all can be done without power cycling the system. For more information please see TN1220, [LatticeXP2 Dual Boot Feature](#).

For more information on device configuration, please see TN1141, [LatticeXP2 sysCONFIG Usage Guide](#).

## Soft Error Detect (SED) Support

LatticeXP2 devices have dedicated logic to perform Cyclic Redundancy Code (CRC) checks. During configuration, the configuration data bitstream can be checked with the CRC logic block. In addition, LatticeXP2 devices can be programmed for checking soft errors in SRAM. SED can be run on a programmed device when the user logic is not active. In the event a soft error occurs, the device can be programmed to either reload from a known good boot image (from internal Flash or external SPI memory) or generate an error signal.

For further information on SED support, please see TN1130, [LatticeXP2 Soft Error Detection \(SED\) Usage Guide](#).

## On-Chip Oscillator

Every LatticeXP2 device has an internal CMOS oscillator that is used to derive a Master Clock (CCLK) for configuration. The oscillator and CCLK run continuously and are available to user logic after configuration is complete. The available CCLK frequencies are listed in Table 2-14. When a different CCLK frequency is selected during the design process, the following sequence takes place:

1. Device powers up with the default CCLK frequency.
2. During configuration, users select a different CCLK frequency.
3. CCLK frequency changes to the selected frequency after clock configuration bits are received.

This internal CMOS oscillator is available to the user by routing it as an input clock to the clock tree. For further information on the use of this oscillator for configuration or user mode, please see TN1141, [LatticeXP2 sysCONFIG Usage Guide](#).

**Table 2-14. Selectable CCLKs and Oscillator Frequencies During Configuration and User Mode**

CCLK/Oscillator (MHz)
2.5 <sup>1</sup>
3.1 <sup>2</sup>
4.3
5.4
6.9
8.1
9.2
10
13
15
20
26
32
40
54
80 <sup>3</sup>
163 <sup>3</sup>

1. Software default oscillator frequency.
2. Software default CCLK frequency.
3. Frequency not valid for CCLK.

## Hot Socketing Specifications<sup>1, 2, 3, 4</sup>

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
$I_{DK}$	Input or I/O Leakage Current	$0 \leq V_{IN} \leq V_{IH} \text{ (MAX.)}$	—	—	+/-1	mA

1. Insensitive to sequence of  $V_{CC}$ ,  $V_{CCAUX}$  and  $V_{CCIO}$ . However, assumes monotonic rise/fall rates for  $V_{CC}$ ,  $V_{CCAUX}$  and  $V_{CCIO}$ .
2.  $0 \leq V_{CC} \leq V_{CC} \text{ (MAX)}$ ,  $0 \leq V_{CCIO} \leq V_{CCIO} \text{ (MAX)}$  or  $0 \leq V_{CCAUX} \leq V_{CCAUX} \text{ (MAX)}$ .
3.  $I_{DK}$  is additive to  $I_{PU}$ ,  $I_{PW}$  or  $I_{BH}$ .
4. LVCMOS and LVTTL only.

## ESD Performance

Please refer to the [LatticeXP2 Product Family Qualification Summary](#) for complete qualification data, including ESD performance.

## DC Electrical Characteristics

### Over Recommended Operating Conditions

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
$I_{IL}$ , $I_{IH}$ <sup>1</sup>	Input or I/O Low Leakage	$0 \leq V_{IN} \leq V_{CCIO}$	—	—	10	$\mu\text{A}$
		$V_{CCIO} \leq V_{IN} \leq V_{IH} \text{ (MAX)}$	—	—	150	$\mu\text{A}$
$I_{PU}$	I/O Active Pull-up Current	$0 \leq V_{IN} \leq 0.7 V_{CCIO}$	-30	—	-150	$\mu\text{A}$
$I_{PD}$	I/O Active Pull-down Current	$V_{IL} \text{ (MAX)} \leq V_{IN} \leq V_{CCIO}$	30	—	210	$\mu\text{A}$
$I_{BHLS}$	Bus Hold Low Sustaining Current	$V_{IN} = V_{IL} \text{ (MAX)}$	30	—	—	$\mu\text{A}$
$I_{BHHS}$	Bus Hold High Sustaining Current	$V_{IN} = 0.7 V_{CCIO}$	-30	—	—	$\mu\text{A}$
$I_{BHLO}$	Bus Hold Low Overdrive Current	$0 \leq V_{IN} \leq V_{CCIO}$	—	—	210	$\mu\text{A}$
$I_{BHHO}$	Bus Hold High Overdrive Current	$0 \leq V_{IN} \leq V_{CCIO}$	—	—	-150	$\mu\text{A}$
$V_{BHT}$	Bus Hold Trip Points		$V_{IL} \text{ (MAX)}$	—	$V_{IH} \text{ (MIN)}$	V
C1	I/O Capacitance <sup>2</sup>	$V_{CCIO} = 3.3\text{V}, 2.5\text{V}, 1.8\text{V}, 1.5\text{V}, 1.2\text{V}$ , $V_{CC} = 1.2\text{V}$ , $V_{IO} = 0$ to $V_{IH} \text{ (MAX)}$	—	8	—	pf
C2	Dedicated Input Capacitance	$V_{CCIO} = 3.3\text{V}, 2.5\text{V}, 1.8\text{V}, 1.5\text{V}, 1.2\text{V}$ , $V_{CC} = 1.2\text{V}$ , $V_{IO} = 0$ to $V_{IH} \text{ (MAX)}$	—	6	—	pf

1. Input or I/O leakage current is measured with the pin configured as an input or as an I/O with the output driver tri-stated. It is not measured with the output driver active. Bus maintenance circuits are disabled.
2.  $T_A$  25°C,  $f = 1.0 \text{ MHz}$ .

## Initialization Supply Current<sup>1, 2, 3, 4, 5</sup>

Over Recommended Operating Conditions

Symbol	Parameter	Device	Typical (25°C, Max. Supply) <sup>6</sup>	Units
$I_{CC}$	Core Power Supply Current	XP2-5	20	mA
		XP2-8	21	mA
		XP2-17	44	mA
		XP2-30	58	mA
		XP2-40	62	mA
$I_{CCAUX}$	Auxiliary Power Supply Current <sup>7</sup>	XP2-5	67	mA
		XP2-8	74	mA
		XP2-17	112	mA
		XP2-30	124	mA
		XP2-40	130	mA
$I_{CCPLL}$	PLL Power Supply Current (per PLL)		1.8	mA
$I_{CCIO}$	Bank Power Supply Current (per Bank)		6.4	mA
$I_{CCJ}$	VCCJ Power Supply Current		1.2	mA

1. For further information on supply current, please see TN1139, [Power Estimation and Management for LatticeXP2 Devices](#).

2. Assumes all outputs are tristated, all inputs are configured as LVCMOS and held at the  $V_{CCIO}$  or GND.

3. Frequency 0 MHz.

4. Does not include additional current from bypass or decoupling capacitor across the supply.

5. A specific configuration pattern is used that scales with the size of the device; consists of 75% PFU utilization, 50% EBR, and 25% I/O configuration.

6.  $T_J = 25^\circ\text{C}$ , power supplies at nominal voltage.

7. In fpBGA and ftBGA packages the PLLs are connected to and powered from the auxiliary power supply. For these packages, the actual auxiliary supply current is the sum of  $I_{CCAUX}$  and  $I_{CCPLL}$ . For csBGA, PQFP and TQFP packages the PLLs are powered independent of the auxiliary power supply.

## LatticeXP2 External Switching Characteristics (Continued)

Over Recommended Operating Conditions

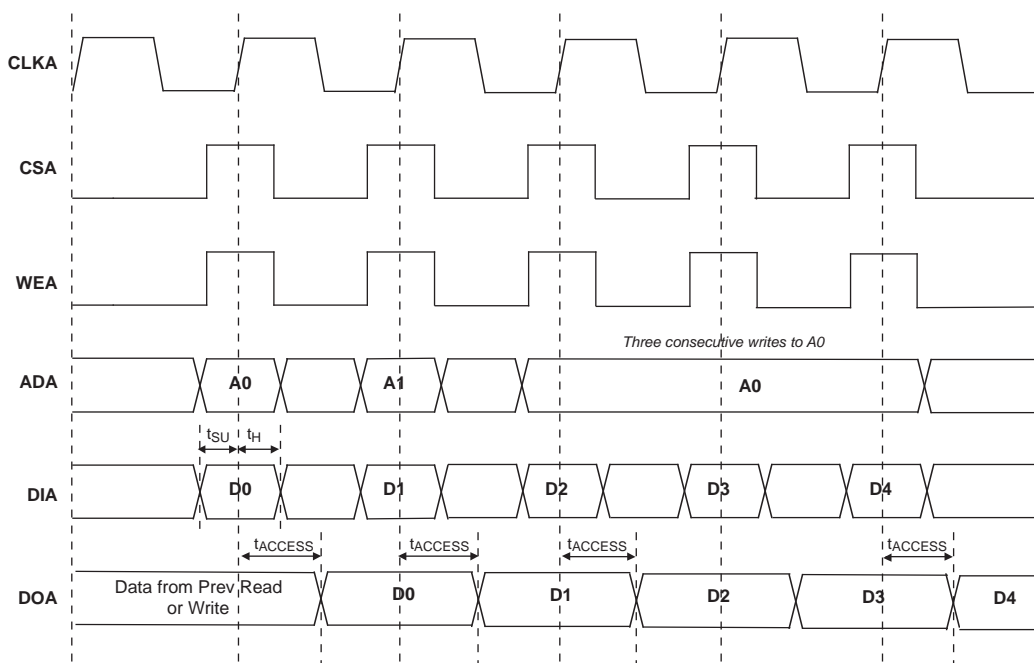
Parameter	Description	Device	-7		-6		-5		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
$t_{HE}$	Clock to Data Hold - PIO Input Register	XP2-5	1.00	—	1.30	—	1.60	—	ns
		XP2-8	1.00	—	1.30	—	1.60	—	ns
		XP2-17	1.00	—	1.30	—	1.60	—	ns
		XP2-30	1.20	—	1.60	—	1.90	—	ns
		XP2-40	1.20	—	1.60	—	1.90	—	ns
$t_{SU\_DELE}$	Clock to Data Setup - PIO Input Register with Data Input Delay	XP2-5	1.00	—	1.30	—	1.60	—	ns
		XP2-8	1.00	—	1.30	—	1.60	—	ns
		XP2-17	1.00	—	1.30	—	1.60	—	ns
		XP2-30	1.20	—	1.60	—	1.90	—	ns
		XP2-40	1.20	—	1.60	—	1.90	—	ns
$t_{H\_DELE}$	Clock to Data Hold - PIO Input Register with Input Data Delay	XP2-5	0.00	—	0.00	—	0.00	—	ns
		XP2-8	0.00	—	0.00	—	0.00	—	ns
		XP2-17	0.00	—	0.00	—	0.00	—	ns
		XP2-30	0.00	—	0.00	—	0.00	—	ns
		XP2-40	0.00	—	0.00	—	0.00	—	ns
$f_{MAX\_IOE}$	Clock Frequency of I/O and PFU Register	XP2	—	420	—	357	—	311	MHz
<b>General I/O Pin Parameters (using Primary Clock with PLL)<sup>1</sup></b>									
$t_{COPLL}$	Clock to Output - PIO Output Register	XP2-5	—	3.00	—	3.30	—	3.70	ns
		XP2-8	—	3.00	—	3.30	—	3.70	ns
		XP2-17	—	3.00	—	3.30	—	3.70	ns
		XP2-30	—	3.00	—	3.30	—	3.70	ns
		XP2-40	—	3.00	—	3.30	—	3.70	ns
$t_{SUPLL}$	Clock to Data Setup - PIO Input Register	XP2-5	1.00	—	1.20	—	1.40	—	ns
		XP2-8	1.00	—	1.20	—	1.40	—	ns
		XP2-17	1.00	—	1.20	—	1.40	—	ns
		XP2-30	1.00	—	1.20	—	1.40	—	ns
		XP2-40	1.00	—	1.20	—	1.40	—	ns
$t_{HPLL}$	Clock to Data Hold - PIO Input Register	XP2-5	0.90	—	1.10	—	1.30	—	ns
		XP2-8	0.90	—	1.10	—	1.30	—	ns
		XP2-17	0.90	—	1.10	—	1.30	—	ns
		XP2-30	1.00	—	1.20	—	1.40	—	ns
		XP2-40	1.00	—	1.20	—	1.40	—	ns
$t_{SU\_DELPLL}$	Clock to Data Setup - PIO Input Register with Data Input Delay	XP2-5	1.90	—	2.10	—	2.30	—	ns
		XP2-8	1.90	—	2.10	—	2.30	—	ns
		XP2-17	1.90	—	2.10	—	2.30	—	ns
		XP2-30	2.00	—	2.20	—	2.40	—	ns
		XP2-40	2.00	—	2.20	—	2.40	—	ns

## LatticeXP2 Internal Switching Characteristics<sup>1</sup>

Over Recommended Operating Conditions

Parameter	Description	-7		-6		-5		Units
		Min.	Max.	Min.	Max.	Min.	Max.	
PFU/PFF Logic Mode Timing								
t <sub>LUT4_PFU</sub>	LUT4 delay (A to D inputs to F output)	—	0.216	—	0.238	—	0.260	ns
t <sub>LUT6_PFU</sub>	LUT6 delay (A to D inputs to OFX output)	—	0.304	—	0.399	—	0.494	ns
t <sub>LSR_PFU</sub>	Set/Reset to output of PFU (Asynchronous)	—	0.720	—	0.769	—	0.818	ns
t <sub>SUM_PFU</sub>	Clock to Mux (M0,M1) Input Setup Time	0.154	—	0.151	—	0.148	—	ns
t <sub>HM_PFU</sub>	Clock to Mux (M0,M1) Input Hold Time	-0.061	—	-0.057	—	-0.053	—	ns
t <sub>SUD_PFU</sub>	Clock to D input setup time	0.061	—	0.077	—	0.093	—	ns
t <sub>HD_PFU</sub>	Clock to D input hold time	0.002	—	0.003	—	0.003	—	ns
t <sub>CK2Q_PFU</sub>	Clock to Q delay, (D-type Register Configuration)	—	0.342	—	0.363	—	0.383	ns
t <sub>RSTREC_PFU</sub>	Asynchronous reset recovery time for PFU Logic	—	0.520	—	0.634	—	0.748	ns
t <sub>RST_PFU</sub>	Asynchronous reset time for PFU Logic	—	0.720	—	0.769	—	0.818	ns
PFU Dual Port Memory Mode Timing								
t <sub>CORAM_PFU</sub>	Clock to Output (F Port)	—	1.082	—	1.267	—	1.452	ns
t <sub>SUDATA_PFU</sub>	Data Setup Time	-0.206	—	-0.240	—	-0.274	—	ns
t <sub>HDATA_PFU</sub>	Data Hold Time	0.239	—	0.275	—	0.312	—	ns
t <sub>SUADDR_PFU</sub>	Address Setup Time	-0.294	—	-0.333	—	-0.371	—	ns
t <sub>HADDR_PFU</sub>	Address Hold Time	0.295	—	0.333	—	0.371	—	ns
t <sub>SUWREN_PFU</sub>	Write/Read Enable Setup Time	-0.146	—	-0.169	—	-0.193	—	ns
t <sub>HWREN_PFU</sub>	Write/Read Enable Hold Time	0.158	—	0.182	—	0.207	—	ns
PIO Input/Output Buffer Timing								
t <sub>IN_PIO</sub>	Input Buffer Delay (LVCMOS25)	—	0.858	—	0.766	—	0.674	ns
t <sub>OUT_PIO</sub>	Output Buffer Delay (LVCMOS25)	—	1.561	—	1.403	—	1.246	ns
IOLOGIC Input/Output Timing								
t <sub>SUI_PIO</sub>	Input Register Setup Time (Data Before Clock)	0.583	—	0.893	—	1.201	—	ns
t <sub>HI_PIO</sub>	Input Register Hold Time (Data after Clock)	0.062	—	0.322	—	0.482	—	ns
t <sub>COO_PIO</sub>	Output Register Clock to Output Delay	—	0.608	—	0.661	—	0.715	ns
t <sub>SUCE_PIO</sub>	Input Register Clock Enable Setup Time	0.032	—	0.037	—	0.041	—	ns
t <sub>HCE_PIO</sub>	Input Register Clock Enable Hold Time	-0.022	—	-0.025	—	-0.028	—	ns
t <sub>SULSR_PIO</sub>	Set/Reset Setup Time	0.184	—	0.201	—	0.217	—	ns
t <sub>HLSR_PIO</sub>	Set/Reset Hold Time	-0.080	—	-0.086	—	-0.093	—	ns
t <sub>RSTREC_PIO</sub>	Asynchronous reset recovery time for IO Logic	0.228	—	0.247	—	0.266	—	ns

**Figure 3-8. Write Through (SP Read/Write on Port A, Input Registers Only)**



Note: Input data and address are registered at the positive edge of the clock and output data appears after the positive edge of the clock.

## FlashBAK Time (from EBR to Flash)

Over Recommended Operating Conditions

Device	EBR Density (Bits)	Time (Typ.)	Units
XP2-5	166K	1.5	s
XP2-8	221K	1.5	s
XP2-17	276K	1.5	s
XP2-30	387K	2.0	s
XP2-40	885K	3.0	s

## JTAG Port Timing Specifications

Over Recommended Operating Conditions

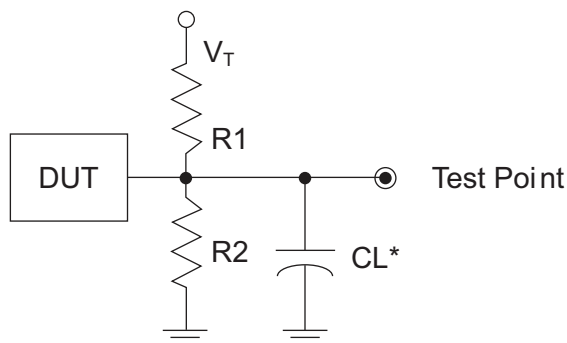
Symbol	Parameter	Min.	Max.	Units
$f_{MAX}$	TCK Clock Frequency	—	25	MHz
$t_{BTCP}$	TCK [BSCAN] clock pulse width	40	—	ns
$t_{BTCPH}$	TCK [BSCAN] clock pulse width high	20	—	ns
$t_{BTCPL}$	TCK [BSCAN] clock pulse width low	20	—	ns
$t_{BTS}$	TCK [BSCAN] setup time	8	—	ns
$t_{BTH}$	TCK [BSCAN] hold time	10	—	ns
$t_{BTRF}$	TCK [BSCAN] rise/fall time	50	—	mV/ns
$t_{BTCO}$	TAP controller falling edge of clock to valid output	—	10	ns
$t_{BTCODIS}$	TAP controller falling edge of clock to valid disable	—	10	ns
$t_{BTCOEN}$	TAP controller falling edge of clock to valid enable	—	10	ns
$t_{BTCRS}$	BSCAN test capture register setup time	8	—	ns
$t_{BTCRH}$	BSCAN test capture register hold time	25	—	ns
$t_{BUTCO}$	BSCAN test update register, falling edge of clock to valid output	—	25	ns
$t_{BTUODIS}$	BSCAN test update register, falling edge of clock to valid disable	—	25	ns
$t_{BTUPOEN}$	BSCAN test update register, falling edge of clock to valid enable	—	25	ns



### Switching Test Conditions

Figure 3-11 shows the output test load that is used for AC testing. The specific values for resistance, capacitance, voltage, and other test conditions are shown in Table 3-6.

**Figure 3-11. Output Test Load, LVTTTL and LVCMOS Standards**



\*CL Includes Test Fixture and Probe Capacitance

**Table 3-6. Test Fixture Required Components, Non-Terminated Interfaces**

Test Condition	R <sub>1</sub>	R <sub>2</sub>	C <sub>L</sub>	Timing Ref.	V <sub>T</sub>
LVTTTL and other LVCMOS settings (L -> H, H -> L)	$\infty$	$\infty$	0pF	LVCMOS 3.3 = 1.5V	—
				LVCMOS 2.5 = $V_{CCIO}/2$	—
				LVCMOS 1.8 = $V_{CCIO}/2$	—
				LVCMOS 1.5 = $V_{CCIO}/2$	—
				LVCMOS 1.2 = $V_{CCIO}/2$	—
LVCMOS 2.5 I/O (Z -> H)	$\infty$	1M $\Omega$		$V_{CCIO}/2$	—
LVCMOS 2.5 I/O (Z -> L)	1M $\Omega$	$\infty$		$V_{CCIO}/2$	$V_{CCIO}$
LVCMOS 2.5 I/O (H -> Z)	$\infty$	100		$V_{OH} - 0.10$	—
LVCMOS 2.5 I/O (L -> Z)	100	$\infty$		$V_{OL} + 0.10$	$V_{CCIO}$

Note: Output test conditions for all other interfaces are determined by the respective standards.

## Signal Descriptions (Cont.)

Signal Name	I/O	Description
TDO	O	Output pin. Test Data Out pin used to shift data out of a device using 1149.1.
VCCJ	—	Power supply pin for JTAG Test Access Port.
<b>Configuration Pads</b> (Used during sysCONFIG)		
CFG[1:0]	I	Mode pins used to specify configuration mode values latched on rising edge of INITN. During configuration, an internal pull-up is enabled.
INITN <sup>1</sup>	I/O	Open Drain pin. Indicates the FPGA is ready to be configured. During configuration, a pull-up is enabled.
PROGRAMN	I	Initiates configuration sequence when asserted low. This pin always has an active pull-up.
DONE	I/O	Open Drain pin. Indicates that the configuration sequence is complete, and the startup sequence is in progress.
CCLK	I/O	Configuration Clock for configuring an FPGA in sysCONFIG mode.
SISPI <sup>2</sup>	I/O	Input data pin in slave SPI mode and Output data pin in Master SPI mode.
SOSPI <sup>2</sup>	I/O	Output data pin in slave SPI mode and Input data pin in Master SPI mode.
CSSPIN <sup>2</sup>	O	Chip select for external SPI Flash memory in Master SPI mode. This pin has a weak internal pull-up.
CSSPISN	I	Chip select in Slave SPI mode. This pin has a weak internal pull-up.
TOE	I	Test Output Enable tristates all I/O pins when driven low. This pin has a weak internal pull-up, but when not used an external pull-up to V <sub>CC</sub> is recommended.

1. If not actively driven, the internal pull-up may not be sufficient. An external pull-up resistor of 4.7k to 10k $\Omega$  is recommended.
2. When using the device in Master SPI mode, it must be mutually exclusive from JTAG operations (i.e. TCK tied to GND) or the JTAG TCK must be free-running when used in a system JTAG test environment. If Master SPI mode is used in conjunction with a JTAG download cable, the device power cycle is required after the cable is unplugged.

### Pin Information Summary (Cont.)

Pin Type		XP2-5				XP2-8				XP2-17			XP2-30			XP2-40	
		132 csBGA	144 TQFP	208 PQFP	256 ftBGA	132 csBGA	144 TQFP	208 PQFP	256 ftBGA	208 PQFP	256 ftBGA	484 fpBGA	256 ftBGA	484 fpBGA	672 fpBGA	484 fpBGA	672 fpBGA
PCI capable I/Os Bonding Out per Bank	Bank0	18	20	20	26	18	20	20	28	20	28	52	28	52	70	52	70
	Bank1	4	6	18	18	4	6	18	22	18	22	36	22	36	54	36	70
	Bank2	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
	Bank3	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
	Bank4	8	8	18	18	8	8	18	26	18	26	36	26	38	54	38	70
	Bank5	14	18	20	24	14	18	20	24	20	24	52	24	53	70	53	70
	Bank6	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
	Bank7	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0

1. Minimum requirement to implement a fully functional 8-bit wide DDR bus. Available DDR interface consists of at least 12 I/Os (1 DQS + 1 DQSB + 8 DQs + 1 DM + Bank VREF1).

### Logic Signal Connections

Package pinout information can be found under “Data Sheets” on the LatticeXP2 product page of the Lattice website [www.latticesemi.com/products/fpga/xp2](http://www.latticesemi.com/products/fpga/xp2) and in the Lattice Diamond design software.

### Thermal Management

Thermal management is recommended as part of any sound FPGA design methodology. To assess the thermal characteristics of a system, Lattice specifies a maximum allowable junction temperature in all device data sheets. Designers must complete a thermal analysis of their specific design to ensure that the device and package do not exceed the junction temperature limits. Refer to the Lattice [Thermal Management](#) document to find the device/package specific thermal values.

### For Further Information

- TN1139, [Power Estimation and Management for LatticeXP2 Devices](#)
- Power Calculator tool is included with the Lattice Diamond design tool or as a standalone download from [www.latticesemi.com/products/designsoftware](http://www.latticesemi.com/products/designsoftware)

## Lead-Free Packaging

### Commercial

Part Number	Voltage	Grade	Package	Pins	Temp.	LUTs (k)
LFXP2-5E-5MN132C	1.2V	-5	Lead-Free csBGA	132	COM	5
LFXP2-5E-6MN132C	1.2V	-6	Lead-Free csBGA	132	COM	5
LFXP2-5E-7MN132C	1.2V	-7	Lead-Free csBGA	132	COM	5
LFXP2-5E-5TN144C	1.2V	-5	Lead-Free TQFP	144	COM	5
LFXP2-5E-6TN144C	1.2V	-6	Lead-Free TQFP	144	COM	5
LFXP2-5E-7TN144C	1.2V	-7	Lead-Free TQFP	144	COM	5
LFXP2-5E-5QN208C	1.2V	-5	Lead-Free PQFP	208	COM	5
LFXP2-5E-6QN208C	1.2V	-6	Lead-Free PQFP	208	COM	5
LFXP2-5E-7QN208C	1.2V	-7	Lead-Free PQFP	208	COM	5
LFXP2-5E-5FTN256C	1.2V	-5	Lead-Free ftBGA	256	COM	5
LFXP2-5E-6FTN256C	1.2V	-6	Lead-Free ftBGA	256	COM	5
LFXP2-5E-7FTN256C	1.2V	-7	Lead-Free ftBGA	256	COM	5

Part Number	Voltage	Grade	Package	Pins	Temp.	LUTs (k)
LFXP2-8E-5MN132C	1.2V	-5	Lead-Free csBGA	132	COM	8
LFXP2-8E-6MN132C	1.2V	-6	Lead-Free csBGA	132	COM	8
LFXP2-8E-7MN132C	1.2V	-7	Lead-Free csBGA	132	COM	8
LFXP2-8E-5TN144C	1.2V	-5	Lead-Free TQFP	144	COM	8
LFXP2-8E-6TN144C	1.2V	-6	Lead-Free TQFP	144	COM	8
LFXP2-8E-7TN144C	1.2V	-7	Lead-Free TQFP	144	COM	8
LFXP2-8E-5QN208C	1.2V	-5	Lead-Free PQFP	208	COM	8
LFXP2-8E-6QN208C	1.2V	-6	Lead-Free PQFP	208	COM	8
LFXP2-8E-7QN208C	1.2V	-7	Lead-Free PQFP	208	COM	8
LFXP2-8E-5FTN256C	1.2V	-5	Lead-Free ftBGA	256	COM	8
LFXP2-8E-6FTN256C	1.2V	-6	Lead-Free ftBGA	256	COM	8
LFXP2-8E-7FTN256C	1.2V	-7	Lead-Free ftBGA	256	COM	8

Part Number	Voltage	Grade	Package	Pins	Temp.	LUTs (k)
LFXP2-17E-5QN208C	1.2V	-5	Lead-Free PQFP	208	COM	17
LFXP2-17E-6QN208C	1.2V	-6	Lead-Free PQFP	208	COM	17
LFXP2-17E-7QN208C	1.2V	-7	Lead-Free PQFP	208	COM	17
LFXP2-17E-5FTN256C	1.2V	-5	Lead-Free ftBGA	256	COM	17
LFXP2-17E-6FTN256C	1.2V	-6	Lead-Free ftBGA	256	COM	17
LFXP2-17E-7FTN256C	1.2V	-7	Lead-Free ftBGA	256	COM	17
LFXP2-17E-5FN484C	1.2V	-5	Lead-Free fpBGA	484	COM	17
LFXP2-17E-6FN484C	1.2V	-6	Lead-Free fpBGA	484	COM	17
LFXP2-17E-7FN484C	1.2V	-7	Lead-Free fpBGA	484	COM	17

Part Number	Voltage	Grade	Package	Pins	Temp.	LUTs (k)
LFXP2-40E-5F484I	1.2V	-5	fpBGA	484	IND	40
LFXP2-40E-6F484I	1.2V	-6	fpBGA	484	IND	40
LFXP2-40E-5F672I	1.2V	-5	fpBGA	672	IND	40
LFXP2-40E-6F672I	1.2V	-6	fpBGA	672	IND	40